

# Product data sheet

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#### **SOT-23**

1. BASE

3. COLLECTOR



#### FEATURE

Ldeally suited for automatic insertion Epitaxial planar die construction Complementary NPN type available(BC817)

### MAXIMUM RATINGS (Ta=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V <sub>CBO</sub>	Collector-Base Voltage	-50	V
V <sub>CEO</sub>	Collector-Emitter Voltage	-45	V
V <sub>EBO</sub>	Emitter-Base Voltage	-5	V
lc	Collector Current -Continuous	-0.5	A
Pc	Collector Power Dissipation	0.3	W
Tj	Junction Temperature	150	°C
T <sub>stg</sub>	Storage Temperature	-55-150	°C

#### ELECTRICAL CHARACTERISTICS (T₂=25℃ unless otherwise specified)

				1	
Parameter	Symbol	Test conditions	Min	Мах	Unit
Collector-base breakdown voltage	V <sub>CBO</sub>	Ι <sub>C</sub> = -10μΑ, Ι <sub>Ε</sub> =0	-50		V
Collector-emitter breakdown voltage	V <sub>CEO</sub>	I <sub>C</sub> = -10mA, I <sub>B</sub> =0	-45		V
Emitter-base breakdown voltage	V <sub>EBO</sub>	Ι <sub>Ε</sub> = -1μΑ, Ι <sub>C</sub> =0	-5		V
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> = -45V, I <sub>E</sub> =0		-0.1	μA
Collector cut-off current	I <sub>CEO</sub>	V <sub>CE</sub> = -40V, I <sub>B</sub> =0		-0.2	μA
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> = -4 V, I <sub>C</sub> =0		-0.1	μA
DC current gain	hfe(1)	V <sub>CE</sub> = -1V, I <sub>C</sub> = -100mA	100	600	
	hfe(2)	V <sub>CE</sub> = -1V, I <sub>C</sub> = -500mA	40		
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> =-500mA, I <sub>B</sub> = -50mA		-0.7	V
Base-emitter saturation voltage	V <sub>BE</sub> (sat)	I <sub>C</sub> = -500mA, I <sub>B</sub> = -50mA		-1.2	V
Transition frequency	f⊤	V <sub>CE</sub> = -5V, I <sub>C</sub> = -10mA f=100MHz	100		MHz

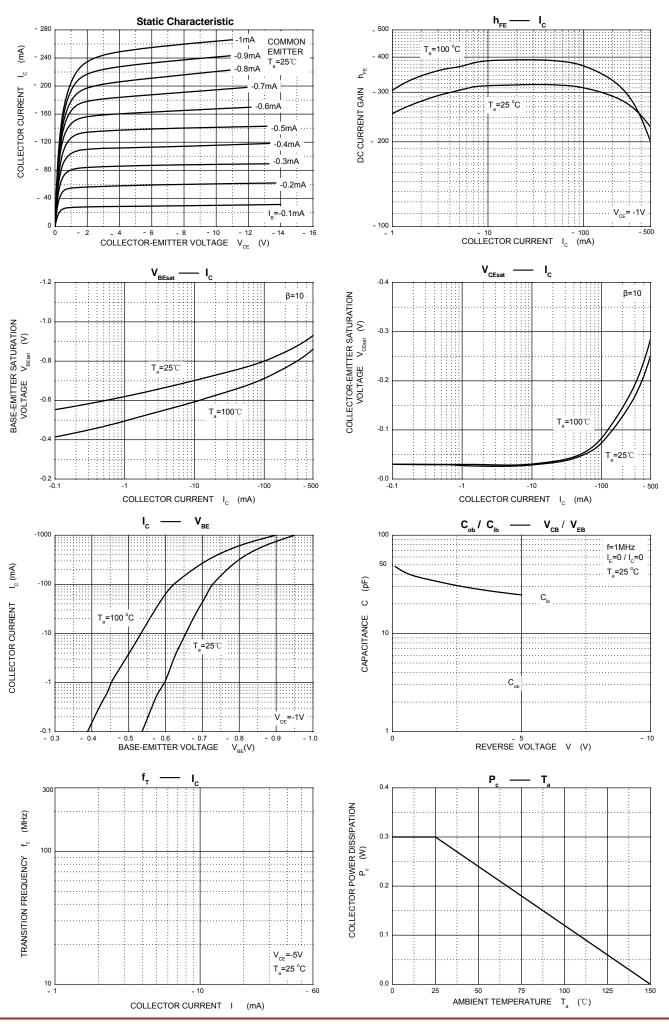
#### CLASSIFICATION OF hFE (1)

Rank	BC807-16	BC807-25	BC807-40
Range	100-250	160-400	250-600
Marking	5A	5B	5C



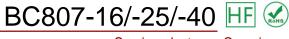
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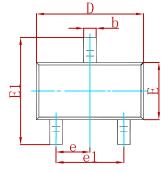
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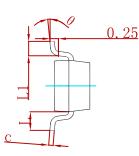


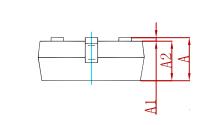


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## PACKAGE MECHANICAL DATA

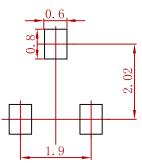






Cumb ol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950	)TYP	0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550	) REF	0.022	2 REF	
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

## Suggested Pad Layout



Note:

Controlling dimension:in millimeters.
General tolerance:± 0.05mm.
The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
BC807-16/-25/-40	SOT-23	3000



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